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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Complete If Known

Application Number	09/535,015
Filing Date	March 24, 2000
First Named Inventor	Shunpei YAMAZAKI et al.
Group Art Unit	2811
Examiner Name	S. Crane
Attorney Docket Number	0756-2131

Sheet	1	of	1
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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²

Examiner Signature	ORANGE	Date Considered	12/2005
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Substitute for form 1448A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	09/535,015
				Filing Date	March 24, 2000
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2811
				Examiner Name	S. Crane
Sheet	1	of	1	Attorney Docket Number	0756-2131

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SWL		5,869,363		Yamazaki et al.	02/09/1999	
{		6,478,263		Yamazaki et al.	11/12/2002	
		5,300,187		Lesk et al.	04/05/1994	
		5,627,086		Noguchi	05/06/1997	
		5,610,737		Akiyama et al.	03/11/1997	
SWL		4,975,760		Dohjo et al.	12/04/1990	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	Foreign Patent Document			Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office ³	Number ⁴	Kind Code ⁵ (if known)		
SWL		JP	05-291220		11/05/1993	Abst.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
SWL		Specification, claims, abstract of Application Serial No. 09/699,466 filed 10/31/2000 to Yamazaki et al.	

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Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known			
				Application Number		09/535,015	
				Filing Date		March 24, 2000	
				First Named Inventor		Shunpei YAMAZAKI et al.	
				Group Art Unit		2811	
				Examiner Name		S. Crane	
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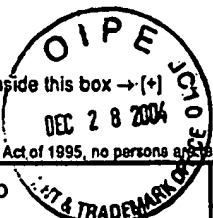
U.S. PATENT DOCUMENTS						
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		Number	Kind Code ² (if known)			
SNL		5,132,754		Serikawa et al.	07/21/1992	

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			Filing Date	March 24, 2000	
			First Named Inventor	Shunpei YAMAZAKI et al.	
			Group Art Unit	2811	
			Examiner Name	S. Crane	
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		Number	Kind Code ² (if known)			
SWC		5,531,862		Otsubo et al.	07/02/1996	
		5,575,883		Nishikawa	11/19/1996	
		5,704,986		Chen et al.	01/06/1998	
		5,902,993		Okushiba et al.	05/11/1999	
		5,970,327		Makita et al.	10/19/1999	
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		6,294,441		Yamazaki	09/25/2001	
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		6,465,287		Yamazaki et al.	10/15/2002	
		6,495,404		Teramoto et al.	12/17/2002	
		6,528,358		Yamazaki et al.	03/04/2003	
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Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
SWC		JP	08-045839			02/16/1996		Abst.
		JP	08-045840			02/16/1996		Abst.
SWC		JP	08-097169			04/12/1996		Abst.

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Atty Docket 0756-2131

Serial No. 09/535,015

INFORMATION DISCLOSURE STATEMENT

Applicants: Shupey YAMAZAKI et al.

Filing Date: March 24, 2000

Group Art Unit: 2825

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SUC	3,389,024	06/18/1968	Schimmer			
	3,783,049	01/01/1974	Sandera			
	4,059,461	11/22/1977	Fan et al.			
	4,068,020	01/10/1978	Reuschel			
	4,132,571	01/02/1979	Cuomo et al.			
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	4,226,898	10/07/1980	Ovshinsky et al.			
	4,231,809	11/04/1980	Schmidt			
	4,271,422	06/02/1981	Ipri			
	4,277,884	07/14/1981	Hsu			
	4,300,989	11/17/1981	Chang			
	4,309,224	01/05/1982	Shibata			
	4,331,709	05/25/1982	Risch et al.			
	4,379,020	04/05/1983	Glaeser et al.			
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	4,481,121	11/06/1984	Barthel			
	4,534,820	08/13/1985	Mori et al.			
	4,544,418	10/01/1985	Gibbons			
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	4,634,473	01/06/1987	Swartz et al.			
	4,735,824	04/05/1988	Yamabe et al.			
	4,755,481	07/05/1988	Faraone			
	4,911,781	03/27/1990	Fox et al.			
	4,959,247	09/25/1990	Moser et al.			
	4,959,700	09/25/1990	Yamazaki			
	4,996,077	02/26/1991	Moslehi et al.			
	4,996,523	02/26/1991	Bell et al.			
	5,043,224	08/27/1991	Jaccodine et al.			
SUC	5,075,259	12/24/1991	Moran			

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INFORMATION DISCLOSURE STATEMENT

Applicants: Shupei YAMAZAKI et al.

Filing Date: March 24, 2000

Group Art Unit: 2825

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SUL	5,089,441	02/18/1992	Moslehi			
	5,112,764	05/12/1992	Mitra et al.			
	5,145,808	09/08/1992	Sameshima et al.			
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	5,173,446	12/22/1992	Asakawa et al.			
	5,200,630	04/06/1993	Nakamura et al.			
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	5,366,926	11/22/1994	Mei et al.			
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	5,470,763	11/28/1995	Hamada			
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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SWC	5,550,070	08/27/1996	Funai et al.			
	5,580,815	12/03/1996	Hsu et al.			
	5,619,044	04/08/1997	Makita et al.			
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	5,693,541	12/02/1997	Yamazaki et al.			
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	5,717,224	02/10/1998	Zhang			
	5,734,179	03/31/1998	Chang et al.			
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SWC	5,990,542	11/23/1999	Yamazaki			

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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SWL	6,005,648	12/21/1999	Zhang et al.			
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SWL	RE 28,386	04/08/1975	Helman et al.			

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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
SWL	0 178 447	10/09/1984	EP			Engl.	
	01-187814	07/27/1989	Japan			Full	
	01-187874	07/27/1989	Japan			Abst.	
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	02-140915	05/30/1990	Japan			Full	
	02-148687	06/07/1990	Japan			Abst.	
	02-275641	11/09/1990	Japan			Abst.	
	03-280418	12/11/1991	Japan			Abst.	
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	05-082442	04/02/1993	Japan			Abst.	
	05-107561	04/30/1993	Japan			Abst.	
	05-299348	11/12/1993	Japan			Abst.	
	06-232059	08/19/1994	Japan			Full	
	07-161634	06/23/1995	Japan			Abst.	
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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No	
SWC	08-129360	05/21/1996	Japan			Abst.	
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Filing Date: March 24, 2000

Group Art Unit: 2825

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Form PTO-1449 (Rev. 8-83)		U.S. Department of Commerce Patent and Trademark Office		Atty Docket 0756-2131		Serial No. 09/535,015	
INFORMATION DISCLOSURE STATEMENT				Applicants: Shupei YAMAZAKI et al.			
				Filing Date: March 24, 2000		Group Art Unit: 2825	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
Examiner Initial							
SWC		Hayzelden et al., "Silicide Formation and Silicide Mediated Crystallization of Nickel-Implanted Amorphous Silicon Thin Films", May 15, 1993, pp. 8279-8289, J. Appl. Phys. 73(12)					
		Kuznetsov et al., "Silicide Precipitate Formation and Solid Phase Re-Growth of Ni-Implanted Amorphous Silicon", April 5-8, 1993, pp. 191-194, Inst. Phys. Conf. Ser. No. 134.4: Proceedings of Royal Microscopical Society Conf.					
		Liu et al., "Polycrystalline Silicon Thin Film Transistors on Corning 7059 Glass Substrates Using Short Time, Low-Temperature Processing", May 17, 1993, pp. 2554-2556, Appl. Phys. Lett. 62(20)					
SWC		Liu et al., "Selective Area Crystallization of Amorphous Silicon Films by Low-Temperature Rapid Thermal Annealing", August 14, 1989, pp. 660-662, Appl Phys. Lett 55(7)					
Examiner		CRANE		Date Considered		5/2005	
<p>*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete If Known

Application Number	09/535,015
Filing Date	March 24, 2000
First Named Inventor	Shunpei YAMAZAKI et al.
Group Art Unit	2811
Examiner Name	S. Crane
Attorney Docket Number	0756-2131

Sheet

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U.S. PATENT DOCUMENTS

Examiner Initials	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SWC		5,940,690		Kusumoto et al.	08/17/1999	
		6,337,232		Kusumoto et al.	01/08/2002	
		6,541,795		Kusumoto et al.	04/01/2003	
		5,888,857		Zhang et al.	03/30/1999	
		6,323,071		Zhang et al.	11/27/2001	
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		6,194,254		Takemura	02/27/2001	
		6,482,686		Takemura	11/19/2002	

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Examiner Initials	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	†
		Office ²	Number ³	Kind Code ⁴ (if known)				
SWC		JP	07-335906			12/22/1995		Abst. & U.S. Equiv.
		JP	07-045519			02/14/1995		Abst. & U.S. Equiv.
		JP	07-231100			08/29/1995		Abst. & U.S. Equiv.
		JP	07-094757			04/07/1995		Abst. & U.S. Equiv.
		JP	07-192998			07/28/1995		Abst.
SWC		JP	05-299339			11/12/1993		Abst. & U.S. Equiv.

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				Application Number		09/535,015	
				Filing Date		March 24, 2000	
				First Named Inventor		Shunpei YAMAZAKI et al.	
				Group Art Unit		2811	
				Examiner Name		S. Crane	
Sheet	2	of	2	Attorney Docket Number		0756-2131	

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SWC		6,162,704		Yamazaki et al.	12/19/2000	
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		6,461,943		Yamazaki et al.	10/08/2002	
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		Office ³	Number ⁴	Kind Code ⁵ (if known)				
SWC		JP	07-066425			03/10/1995		Abst. & U.S. Equiv.
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		JP	08-045840			02/16/1996		Abst. & U.S. Equiv.
		JP	08-097169			04/12/1996		Abst. & U.S. Equiv.
SWC		KR	96-005879			02/23/1996		U.S. Equiv.

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
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				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2811
Examiner Name	S. Crane				
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Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
SWC		4,759,610		Yanagisawa	07/26/1988	
SWC		5,535,471		Guldi	07/16/1996	
SWC		5,661,056		Takeuchi	08/26/1997	

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Examiner Initials ¹	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
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SWC		Wolf, <i>Silicon Processing for the VLSI ERA</i> , Volume 2: Process Integration, Page 274 (1990)	

Examiner Signature	CRANE	Date Considered	11/6/03
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				Filing Date	March 24, 2000
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2811
				Examiner Name	S. Crane
Sheet	1	of	1	Attorney Docket Number	0756-2131

U.S. PATENT DOCUMENTS						
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		Number	Kind Code ² (if known)			
SWC		5,306,651		Masumo et al.	04/26/1994	
		5,893,730		Yamazaki et al.	04/13/1999	
		5,932,893		Miyanaga et al.	08/03/1999	
		6,133,073		Yamazaki et al.	10/17/2000	
		6,225,152	B1	Yamazaki et al.	05/01/2001	
SWC		6,288,412	B1	Harnada et al.	09/11/2001	
		6,323,072	B1	Yamazaki et al.	11/27/2001	

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				Application Number	09/535,015	
				Filing Date	March 24, 2000	
				First Named Inventor	Shunpei YAMAZAKI et al.	
				Group Art Unit	2811	
Examiner Name	S. Crane					
Attorney Docket Number	0756-2131					
Sheet	1	of	1			

U.S. PATENT DOCUMENTS						
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		Number	Kind Code ² (if known)			
SGC		5,591,988		Arai et al.	01/07/1997	
		5,953,597		Kusumoto et al.	09/14/1999	
SWC		6,011,275		Ohtani et al.	01/04/2000	
		6,331,718		Yamazaki et al.	12/18/2001	

FOREIGN PATENT DOCUMENTS							
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Office ³	Number ⁴	Kind Code ⁵ (if known)			
SWC		JP	06-314785		Suzawa et al.	11/8/1994	Abstract
SWC		JP	06-314787		Suzawa et al.	11/8/1994	Abstract

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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Form PTO 1449 (Rev. 8-63) JAN 04 2002 INFORMATION DISCLOSURE STATEMENT		U.S. Department of Commerce Patent and Trademark Office		Atty Docket 0756-2131		Serial No. 09/535,015	
		Applicants: Shupei YAMAZAKI et al.				Filing Date: March 24, 2000	
						Group Art Unit: 2825	
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
SWC	5,728,259	03/17/1998	Suzawa et al.				
Examiner CRANE				Date Considered 10/18/02			
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Atty Docket 0756-2001

Serial No. 09/535,015

INFORMATION DISCLOSURE STATEMENT

Applicants: Shupei YAMAZAKI et al.

Filing Date: March 24, 2000

Group Art Unit: 2825

SEP 05 2001

PATENT & TRADEMARK OFFICE

5. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SWC	3,890,632	06/17/1975	Ham et al.			
	4,330,363	05/18/1982	Biegesen et al.			
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	5,686,328	11/11/1997	Zhang et al.			
	5,763,899	06/09/1998	Yamazaki et al.			
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	5,929,527	07/27/1999	Yamazaki et al.			
	5,949,107	09/07/1999	Zhang			
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	6,083,801	07/04/2000	Ohtani.H			
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	6,147,667	11/14/2000	Yamazaki et al.			
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Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation Yes No
SWC	07-335900	12/22/1995	JP			Eng Abst

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Examiner Initial	
SWC	Baker, Jr. et al., "Field Effect Transistor", pp. 849, 1968, IBM Technical Disclosure Bulletin, Vol. 11, No. 7

Examiner CRANE

Date Considered 7/7/03

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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				Applicant: Shunpei YAMAZAKI et al.		1c598 U.S. PTO 09/535015  09/24/00	
				Filing Date: March 24, 2000			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)	
SWC	5,403,772	04/04/95	Zhang et al				
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	5,534,716	07/09/96	Takemura				
	5,543,352	08/06/96	Ohtani et al				
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SWC	R.J. Nemanich et al, "Structure and Growth of the Interface of Pd on α -SiH", The American Physical Society - Physical Review, Vol. 22, No. 12, pp. 6828-6831, June 1981						
SWC	M.J. Thompson et al, "Silicide Formation in Pd- α -Si:H Schottky Barriers", Appl. Phys. Lett., Vol. 39, No. 3, pp. 274-276, August 1981						
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SWC	R.J. Nemanich et al, "Initial Phase Formation at the Interface of Ni, Pd, or Pt and Si", Mat. Res. Soc. Symp. Proc., Vol. 25, 1984						
Examiner CRANG				Date Considered 10/18/02			
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Applicant: Shunpei YAMAZAKI et al.

Filing Date: March 24, 2000

Group: 2811

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
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	5,595,944	01/21/97	Zhang et al			
	5,604,360	02/18/97	Zhang et al			
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	5,654,203	08/05/97	Ohtani et al			
	5,656,825	08/12/97	Kusumoto et al			
	5,663,077	09/02/97	Adachi et al			
	5,700,333	12/23/97	Yamazaki et al.			
	5,677,549	10/14/97	Takayama et al.			
	5,696,386	12/9/97	Yamazaki			
	5,696,388	12/9/97	Funada et al.			
SWC	5,705,829	1/6/98	Miyanaga et al.			

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Applicant: Shunpei YAMAZAKI et al.

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U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
SWC	5,712,191	01/27/98	Nakajima et al.			
	5,756,364	05/26/98	Tanaka et al.			
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